R&D for a digital TPC The SiTPC project

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(CERN, Freiburg, MESA+/Twente, NIKHEF, Saclay)

•The digital TPC concept and advantages

•VLSI electronics: from Medipix2 to TimePix

Micromegas and GEM achievements

•Integrated grid

Protection issues

Aging studies

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The digital TPC concept

•Reconstruct a track electron by electron (or cluster by cluster)

•Optimally use this basic information:

•Insensitive to gain fluctuations

 ·dE/dx optimal resolution from cluster counting

•If you cover the whole TPC surface, $O(10^{8-9})$ channels instead of 10⁶, but all digital (1/0)

•First costing attempts show it is comparable or cheaper than a standard readout

•Can consider replacing a few pad-rings by digital anode chips (gas club sandwich)

formation: ctuations ion from C surface, f 10⁶, but all

• • • • • •

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Gain fluctuations

•In first approximation, gain fluctuates exponentially in a parallelplate chamber.

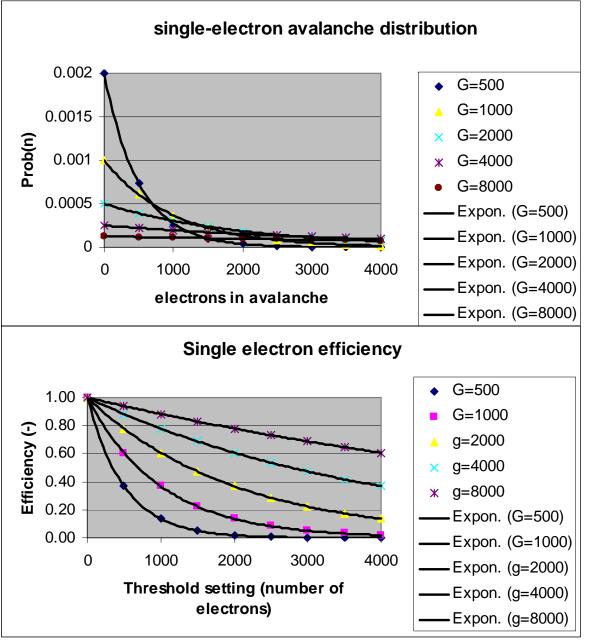
•In presence of noise, a 4 or 5 st.dev. cut costs in efficiency for single electron

•A gain of 19000 was necessary to see the single electrons with 90% efficiency

•Sparks destroy the chips

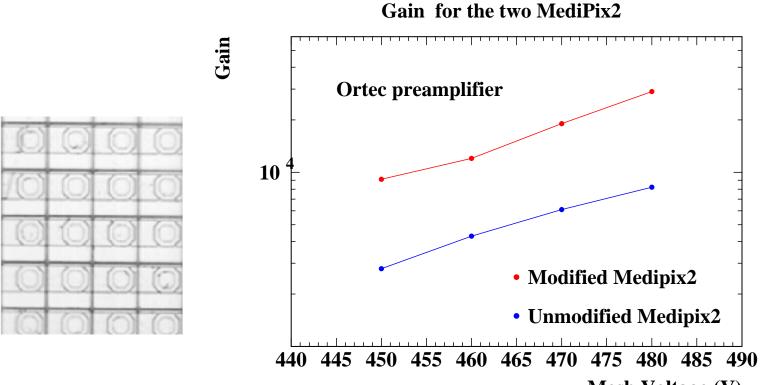
- -> LOWER NOISE
- -> PROTECT CHIPS

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Gain with He+20% isobutane

•The gain with modified Medipix (80% conductive surface) is 3 to 4 times larger than with unmodified Medipix (20% conductive surface)

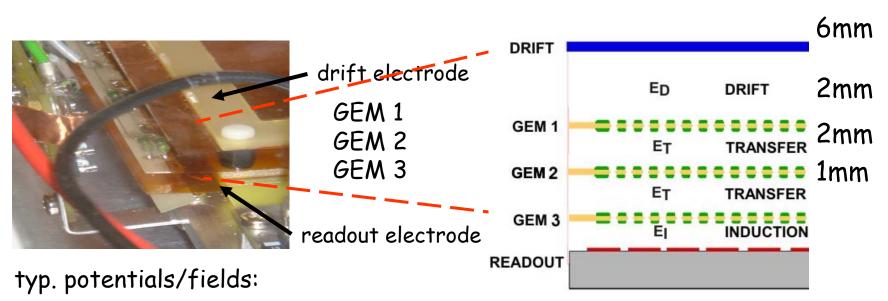


Mesh Voltage (V)

P. Colas, Digital TPC R&D

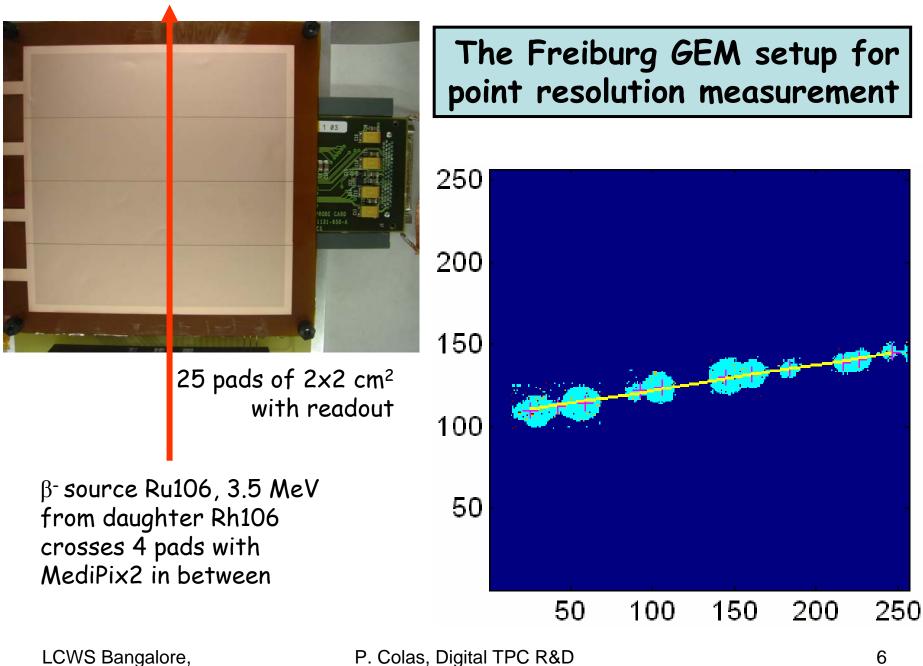
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The Freiburg GEM setup



 E_D = 1.1 kV/cm ΔV_{GEM} = 404 V E_T = 3.2 kV/cm E_I = 4.0 kV/cm LCWS Bangalore,

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Resolution

Two methods:

residuals of a straight line fit and triplet method

			. 1
1	Ar/CO2	He/CO2	- 002 -
residuals (str. line)*	$65 \pm 1.4 \ \mu m$	$51 \pm 2.5 \ \mu m$	- 000 - 150 - 150 - 100 - 100
Triplet meth	57 ± 1.3 μm	$53 \pm 2.8 \ \mu m$	50 - 0 -
resolution,	x	1	-15
Difference understood:			
Due to multiple scattering			triplet method:

residuals from straight line fit to electron tracks Ar/CO2 300 Data: Data2_A Model: Gauss 250 = 1.45287 Chi^2/DoF = 0.95273 0.80996 ±0.2006 00 ±0.03211 -0.025432sigma 2.39511 ±0.05204 ±18.99149 711.86175 50 $= 64.5 \ \mu m$ σ 00 50 ×______ 0. ------------15 -10 10 15 -5 0 5 residual [pixel] residual n

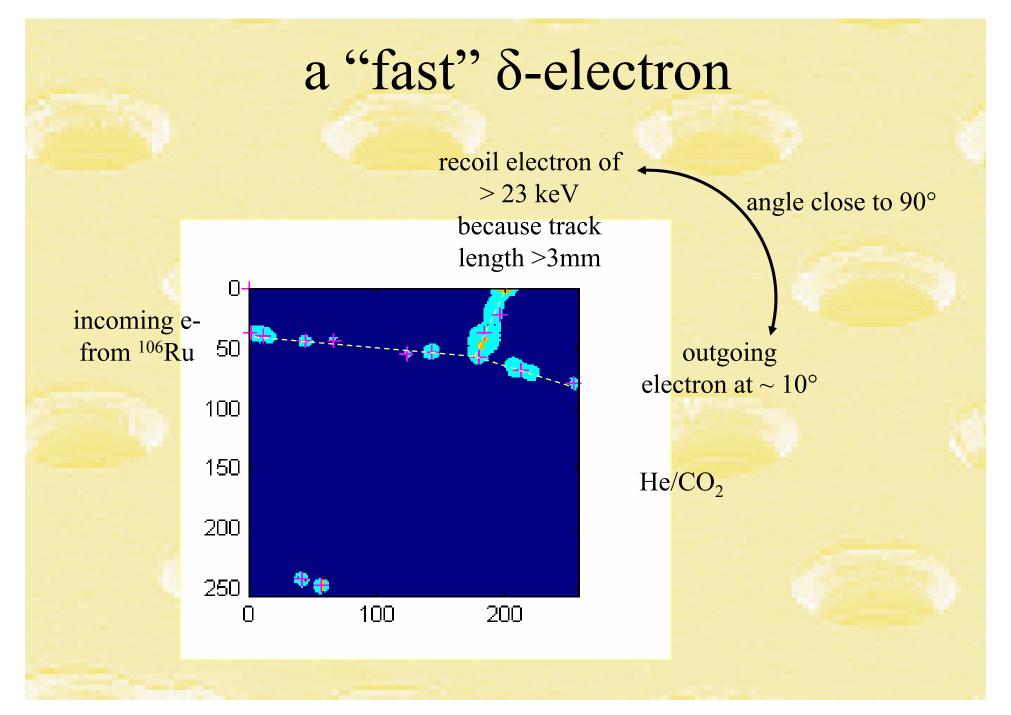
residuals reweighted by a factor close to $\sqrt{(2/3)}$

n-1

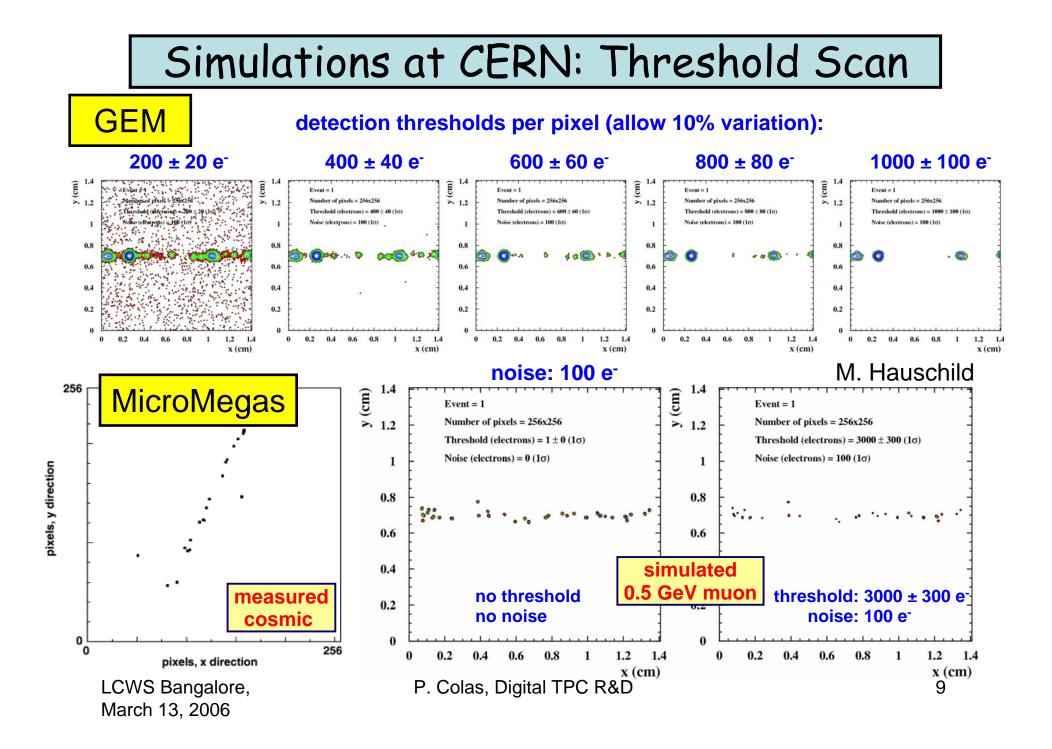
* slightly biased, still under investigation

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n+1



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From Medipix2 to Timepix

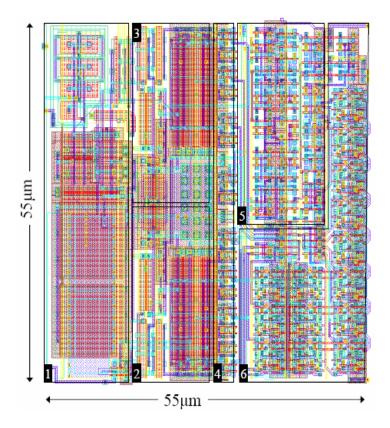
•Medipix collaboration: 17 institutes, since 1999

-CMOS chip, 0.25 μ technology, 65000 pixels on 2cm²

•Upgrade of Medipix2: MXR version, less sensitive to temperature, finer setting of the pedestals pixel by pixel

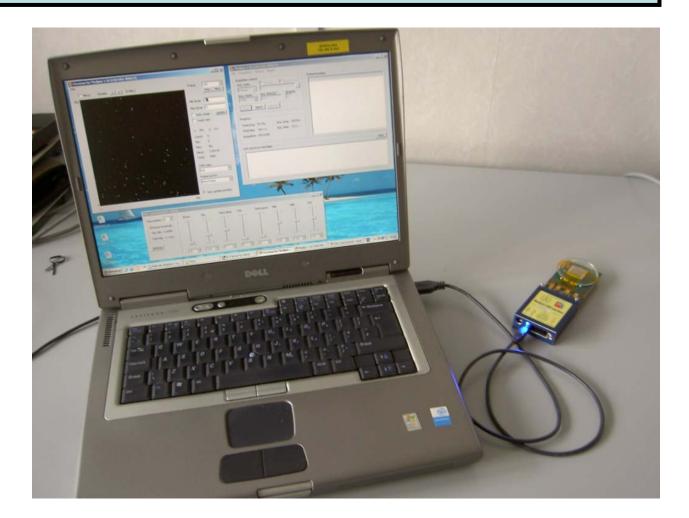
•Also new readout board/card: USB (so far 6x slower than MUROS board)





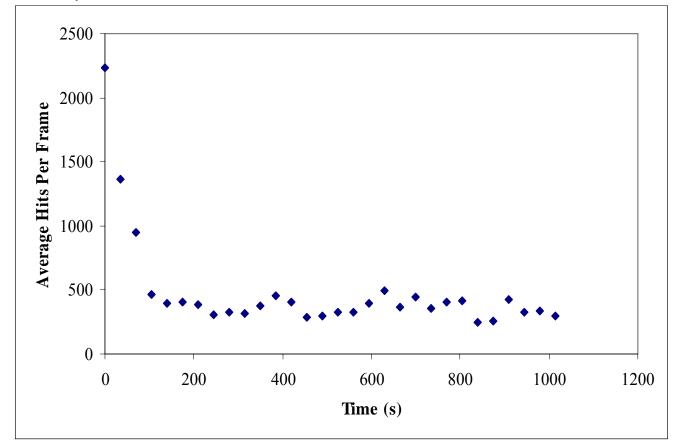
1 pixel = preamp (1)+ 2discri (2,3) + 8-bit DACs (4)+ 14-bit counter (6)

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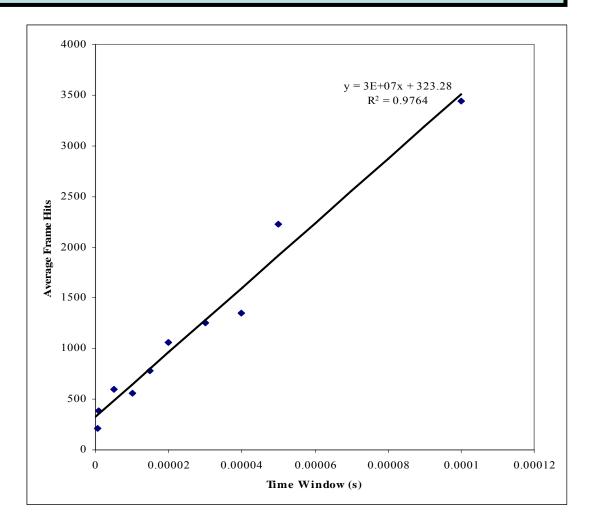
Noise vs. Running Time (from cold) Medipix2/MXR Chip J07



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Average number of hits vs time, for threshold at median noise:

Slight offset

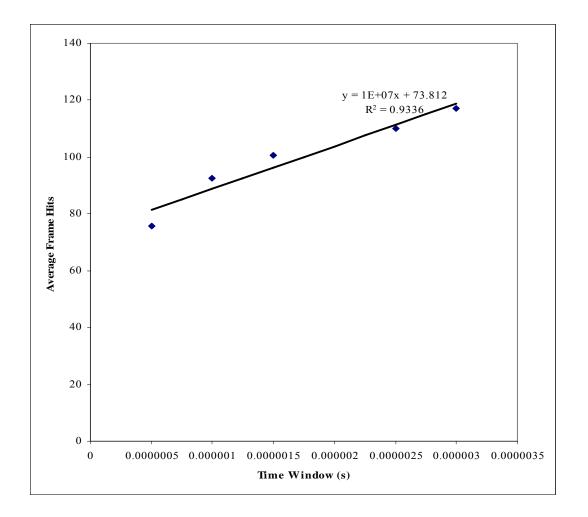


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Average number of hits vs time, for threshold 1 step higher

Offset larger in relative value

This means that there is correlated noise, thus room for improvement



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From Medipix2 to Timepix

Minimize changes to limit risks

•Provide a time measurement : distribute the clock (10 to 100 MHz) on every pixel (a clock per pixel was envisaged, but clock frequency is a function of power)

•Columns of ring oscillators with current starving are used for this (column buffered clock)

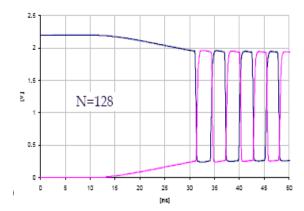
•Switchable Time-Over-Threshold (provides spectral capability) pixel by pixel.

•Provide protection by a resistive layer (3 microns of hydrogenated amorphous silicon, $10^{10-12} \Omega.cm$), equivalent to a $O(100 M\Omega)$ resistor which discharges slowly the mesh and lowers HV locally

•OK for our signals 1/C Ω << R (C~20 fF)

•TEST IN PROGRESS

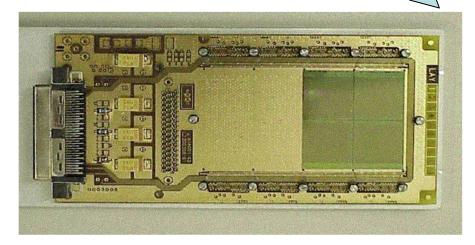
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Further Developments

RELAXD project (Dutch/Belgian) NIKHEF,Panalytical,IMEC,Canberra:

- Chip tiling: large(r) detector surfaces (2x2, 2x4 chips)
- Through Si connectivity: avoiding bonding wires
- Fast readout technology (~5 Gb/s)

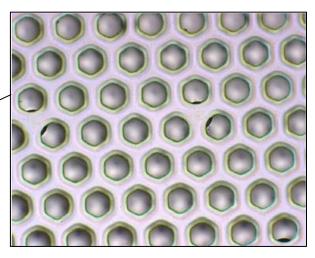


Further development: InGrid (MESA+/Twente, NIKHEF)

Integrating the Micromegas by Silicon wafer post-processing allows:

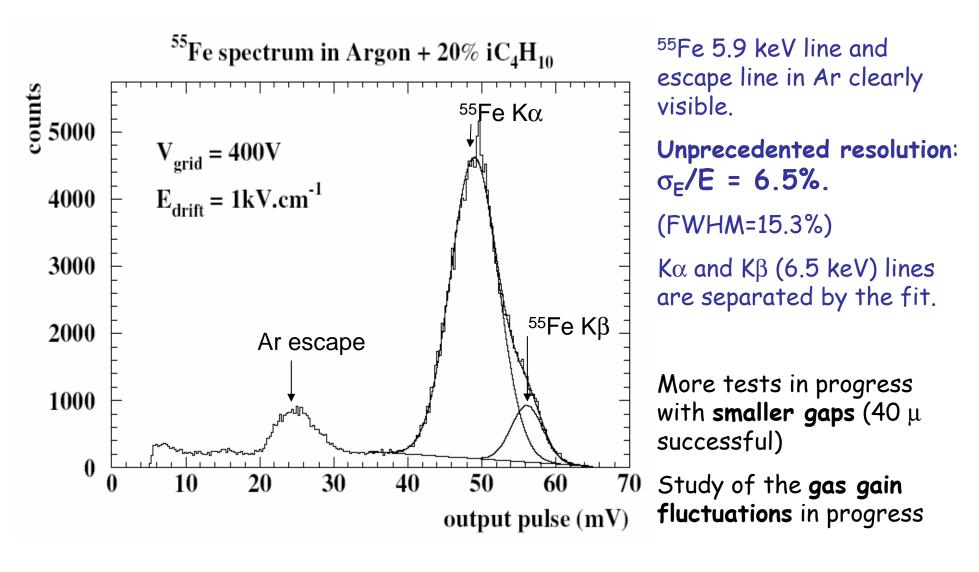
- to avoid Moire effects (perfect alignment) and gap variations
- to avoid dead areas, like frames (even hidden pillars)
- to segment the mesh (lower noise, more reliability)





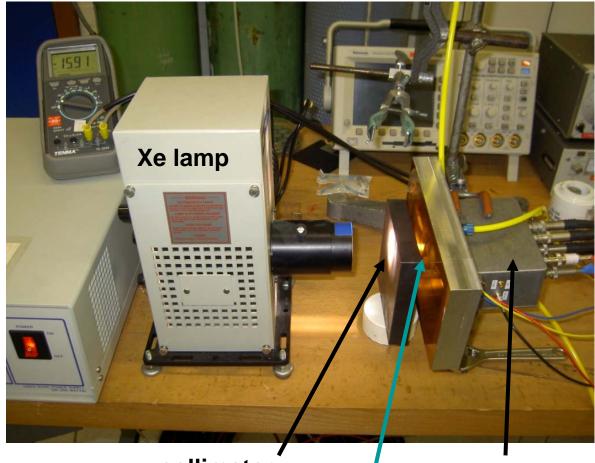
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Results with Argon + 20% isobutane



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Aging studies in NIKHEF and Saclay



January 2006 at NIKHEF:

Use a Xe lamp to produce photo-electrons on a mesh

Broke record of current in a MPGD: 150 micro-Ampere on 65 mm² !

(equivalent to 5 years of LHC at 30cm from the beam in one hour)

Aging studies continue, with this Xe lamp in NIKHEF and with a X-ray gun in Saclay

collimator

Micromegas detector

UV window

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Future: EUDET/SiTPC



•Kick-off meetings held at NIKHEF and DESY in January and February '06. Clear milestones with deliverables 2006 through 2009

- •CERN-Freiburg-NIKHEF-Saclay (+ soon Bonn? Bucarest?), open to newcomers. 2M€+, of which 850 k€ allocated by EC.
- •TimePix design at CERN (until June 2006)
- •Develop post-processings for protection and mesh integration
- •Return from submit this summer, then perform tests (and iterate?)
- •Build a detector (deliverable in 2 years)
- •Watch the outcome of 130 nm and 90 nm technologies (CERN)